

**Search Notes**

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VAN T. PHAM

Applicant(s)/Patent under  
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OHYAMA, MINORU

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner
369	112.16, 121.	5/26/2006	VP

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB)  369, (text search only see search history printout).	5/26/2006	VP
Consulted WayneYoung.	5/26/2006	VP